

602 Sputter Deposition System

"Collaboration

with the

Customer is

essential to

arriving at

optimum

solutions."

DEPOSITION PRODUCTS & PROCESSES

The 602 Series Systems

"Collaboration with the Customer is essential to arriving at optimum solutions."

Understanding this principle has guided MeiVac through more than thirty years of providing products and processes.

Searching for solutions with our customers is central to attaining the predictable results necessary to meet the most stringent processing requirements.

The MeiVac 602 series was developed as a high reliability, high uptime, expandable system platform. The first in this series was the MeiVac 602G, a single process chamber system for the deposition of thin alumina gap layers.

Responding to the need for higher productivity of increasingly sophisticated thin film manufacturing processes, MeiVac recently introduced the MeiVac 602 two and three chamber cluster tools, the next deposition system in the series. This system was developed especially for applications where it is essential to provide chamber isolation, maintain vacuum between process steps, or for higher throughput when running a single process.

Consistent with the modular architecture of the MeiVac 602 family, the multi-chamber cluster tools share a large number of sub-systems. For example, all systems utilize the same robot, as well as loadlock and transfer chambers. For many applications, they incorporate the same process chamber. All this results in a newly introduced system that contains many major modules that have already been proven in production in MeiVac 602 single chamber systems.

Such a multi-chamber approach allows the MeiVac 602 to address the increasingly complex needs of MeiVac's core alumina Thin Film Head market, as well as other advanced thin film applications.

TYPICAL TOOL LAYOUTS









MeiVac 602 series systems are automated, loadlocked, single substrate deposition tools optimized for dielectric, magnetic and conductive layers used in Thin Film Magnetic Heads. The systems deposit in the static, sputter-down mode with a variety of RF or DC sources. The modular design and MESC compatibility allow for efficient operation in both R&D and production environments, with single or multiple process module configurations.

The transfer module consists of a loadlock chamber with an elevator for loading and unloading substrates, a transfer chamber with a robotic arm for transferring the substrates to and from the different process/loadlock chambers, and related vacuum measurement and control facilities. The transfer chamber can be provided with vacuum isolation from the loadlock chamber.

Today's magnetic recording heads require the deposition of ever thinner alumina layers. The MeiVac 602G deposition system provides superior film properties for ultra-thin gap layers.

The 602G can be used for deposition of alumina or alternative gap material by various conventional and reactive sputtering techniques.

The 602B deposition system extends the processing accuracy and speed for increasingly thin basecoats, while providing the improved defect controls that can only be found in loadlocked systems. It incorporates two process chambers for deposition of alumina layers that are typically <10 microns thick. Its process modules are identical to the ones used in the field proven MieVac 602G with larger RF power source allowing 30% higher deposition rates. The system delivers the high reliability essential in a production environment, while depositing alumina layers with uniformities in the 1-2% range, at throughputs that, depending on thickness, exceed those of MeiVac's HEDA 2460 and 2480, the long-standing products of choice for this application.





Control and monitoring of the 602 series systems are accomplished through a computer-based system working with a Programmable Logic Controller. An advanced point-and-click Graphical User Interface provides easy access and control of the software and hardware. Multi-level password protection allows different operation access levels while maintaining ease of functional control.

CONTROL SYSTEM

- Point-and-click actuated intuitive icon-driven GUI for ease of operation and high functional visibility.
- Complete recipe management and wafer load map, which assigns a recipe to a wafer.
- Data logging capabilities for storing process parameter values, with auto data logging and self-cleanup features.
- Five levels of automation and control from fully automated to fully manual
- Interlock control (both hardware & software) configured appropriately to the chosen operational mode.

MEIVAC

Meilac

NAVIGATION BUTTON AND GRAPHICAL ICON ACCESS

| MeiVac | | Auto 41257 PM 5 | ye Mgr About | |
|---------------------|--|--------------------|--------------------|--|
| INCO DETROSIT | U + 10 ⁻⁷ 7 | | CI DEPOSIT | |
| Ellery | - | Tree . | - | |
| | | | Pumping Depped | |
| | | | FULL AUTO STOP | |
| | | | FULL AUTO START | |
| | 10 ⁻² T 25 × 10 ⁻² T | | VENT | |
| LOAD | OCK Pureins Discout | 3 | | |
| Laadlock System | Recipes Deta | | Me | |
| Chamber 2 Chamber 1 | Manual Security | 11 2 | Alara | |

SYSTEM SCREEN



WAFER LOADMAP SCREEN



LOADLOCK SCREEN



RECIPE EDIT SCREEN

PROCESS CHAMBER SCREEN

Auto Log Dri e et et PM Sys Mgr

Auto Log On 600 S 83.43 PM Sys Mgr AM

SEMI-AUTOMATIC SCREEN

THIN FILM MAGNETIC HEADS

HARD-BIASED MAGNETORESISTIVE (MR) HEAD



The Hard Disk Drive Industry has a history of unprecedented technological growh with data storage capacities increasing exponentially. The introduction of spin valve and perpendicular recording technology is driving areal densities at a CAGR of 60% while prices continue to drop. The main limitations on the size of the smallest bit that can be reliably written and read are head design. These developments in thin film head technologies call for increasingly sophisticated thin film manufacturing processes. The ability to accurately reproduce precise layers is key to continued progress.

Gap Application

Insulating gap layers are used to physically and electrically separate various conducting layers in a thin film head. The read element of the head is separated from the bottom and top shields by insulating gap layers (half gaps). In merged heads, the top shield also serves as the pottom pole of the inductive write element. The active part of the inductive element is a multi-turn, multilayer copper coil separated from the bottom and top poles by a gap layer.

Production of thin, precise gap layers with excellent dielectric properties and smooth surfaces are key for new generation spin valve and perpendicular recording heads. As areal densities skyrocket head size with continue to shrink, requiring gaps a few nanometers thick. This requires deposition techniques that keep substrate temperature low, while producing gap materials that possess high breakdown strength and thermal conductivity, as well as low defect density (pinholes) and electrical leakage. Step coverage also becomes a very critical issue for ultra-thin layers, since low values can lead to magnetic field leakage and drastic reductions in head performance. The 602 family offers improved edge coverage and stress control with RF bias while maintaining low substrate temperature with Helium Backside Cooling.

Basecoat Application

One of the first processes in head fabrication is to deposit a layer of alumina. These under layers of alumina (10-20 micros thick) provide a basecoat over which the rest of the head is constructed. Like gap layers, the thickness of basecoat layers is also decreasing with more stringent uniformity and defect density requirements.

SYSTEMS SPECIFICATIONS



602-2 FRONT VIEW

602-2 FOOTPRINT

602-3 FRONT VIEW

602-3 FOOTPRINT

| | MeiVac 602-2 | MeiVac 602-3 | | | | |
|--|---|--|---|--|--|--|
| Throughput | Typically 40 minutes of overhead for cassette loading, transfer, pumping, and venting per cassette plus deposition time (400A/minute) | Typically 40 minutes of overhead for cassette loading, transfer, pumping, and venting per cassette plus deposition time (650A/minute) Approximately 11000 lbs | | | | |
| System Weight | Approximately 8000 lbs | | | | | |
| 602 TECHNICAL SPECIFICATIONS | | | | | | |
| Ultimate Pressure Process | 3 x 10 ⁻⁷ Torr 3 x 10 ⁻⁶ Torr 3 x 10 ⁻⁶ Torr (Shared pumping stack with loadlock) | Wafer Capacity Heating | Up to 25 wafers per cassette | | | |
| Loadlock | | | Separate chamber can be provided for Substrate preheat | | | |
| Iransfer | | Target Sizes | 14" Diameter, RF Diode | | | |
| Sputtering Sources RF Diode RF Magnetron DC Magnetron | RF Diode | | 12" Diameter, Magnetron (RF or DC) | | | |
| | RF Magnetron | Uniformity | ±2.0% Max/Min | | | |
| | DC Magnetron | Etching | Sputter etch in process chamber | | | |

 5830 Hellyer Avenue San Jose, CA 95138 Tel: (408) 362-1000 Fax: (408) 362-1010 www.meivac.com See web for Rep.

QUALITY VACUUM SYSTEMS & PRODUCTS